

**Notice of References Cited**

Application/Control No.

09/835,205

Applicant(s)/Patent Under  
Reexamination  
SUGAWARA ET AL.

Examiner

Bach Q Vuong

Art Unit

2653

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,084,843	07-2000	Abe et al.	369/112.07
	B	US-6,507,009	01-2003	Ohnishi et al.	250/201.2
	C	US-6,236,633	05-2001	Chang et al.	369/112.1
	D	US-6,646,975	11-2003	Uchizaki et al.	369/121
	E	US-6,358,764	03-2002	Nemoto, Kazuhiko	438/22
	F	US-6,043,911	03-2000	Yang, Keun Young	359/15
	G	US-6,091,691	07-2000	Yoo et al.	369/112.11
	H	US-5,986,998	11-1999	Park, Soo-han	369/121
	I	US-6,480,456	11-2002	Kawamura et al.	369/120
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Tle